

CDx4HC4040、CDx4HCT4040 高速 CMOS 逻辑 12 级二进制计数器

1 特性

- 全静态运行
- 缓冲输入
- 通用复位
- 负边沿脉冲
- 扇出 (在温度范围内)
 - 标准输出: 10 个 LSTTL 负载
 - 总线驱动器输出: 15 个 LSTTL 负载
- 宽工作温度范围: -55°C 至 125°C
- 平衡的传播延迟时间及转换时间
- 与 LSTTL 逻辑 IC 相比, 功耗显著降低
- HC 类型
 - 工作电压为 2V 至 6V
 - 高抗噪性: 当 $V_{\text{CC}} = 5\text{V}$ 时, $N_{\text{IL}} = V_{\text{CC}}$ 的 30%
- HCT 类型
 - 工作电压为 4.5V 至 5.5V
 - 直接 LSTTL 输入逻辑兼容性, $V_{\text{IL}} = 0.8\text{V}$ (最大值), $V_{\text{IH}} = 2\text{V}$ (最小值)
 - CMOS 输入兼容性, 当电压为 V_{OL} 、 V_{OH} 时, $I_{\text{I}} \leq 1\mu\text{A}$

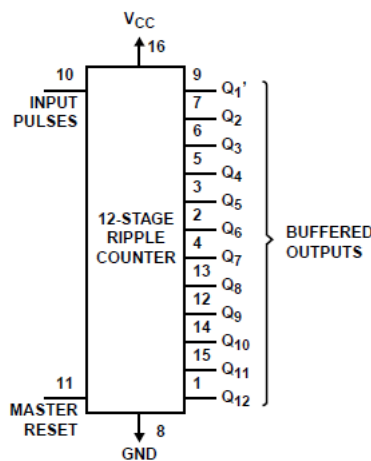
2 说明

'HC4040 和 'HCT4040 是 14 级纹波进位二进制计数器。所有计数器级均为控制器触发器。输入脉冲每出现一次负时钟转换, 级的状态计数加一; MR 线上出现高电压电平会将所有计数器重置为零状态。所有输入和输出均采用缓冲机制。

器件信息

器件型号	封装 ⁽¹⁾	封装尺寸 (标称值)
CD54HC4040	J (CDIP、16)	24.38mm × 6.92mm
CD54HCT4040	J (CDIP、16)	24.38mm × 6.92mm
CD74HC4040	D (SOIC、16)	9.90mm × 3.90mm
	N (PDIP、16)	19.31mm × 6.35mm
CD74HCT4040	D (SOIC、16)	9.90mm × 3.90mm
	N (PDIP、16)	19.31mm × 6.35mm

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。



功能方框图



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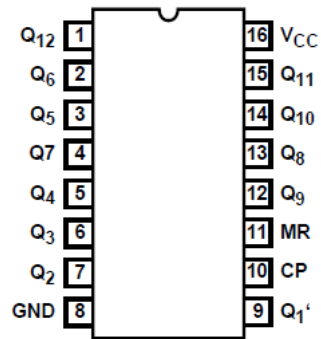
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3 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision D (October 2003) to Revision E (July 2022)	Page
• 更新了整个文档中的编号、格式、表格、图和交叉参考，以反映现代数据表标准.....	1

4 Pin Configuration and Functions



J, D, or N package
16-Pin CDIP, SOIC, or PDIP
Top View

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage range	- 0.5	7	V
I _{IK}	Input clamp current ⁽²⁾	(V _I < - 0.5 V or V _I > V _{CC} + 0.5 V)	± 20	mA
I _{OK}	Output clamp current ⁽²⁾	(V _O < - 0.5 V or V _O > V _{CC} + 0.5 V)	± 20	mA
I _O	Output source or sink current per output pin	(V _O > - 0.5 V or V _{CC} + 0.5 V)	± 25	mA
	Continuous current through V _{CC} or GND		± 50	mA
T _J	Junction temperature		150	°C
T _{stg}	Storage temperature	- 65	150	°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

5.2 Recommended Operating Conditions⁽¹⁾

		MIN	MAX	UNIT	
V _{CC}	Supply voltage range	HC types	2	6	V
		HCT types	4.5	5.5	
V _I , V _O	DC input or output voltage	0	V _{CC}	V	
	Input rise and fall time	2 V	1000	ns	
		4.5 V	500		
		6 V	400		
T _A	Temperature range	- 55	125	°C	

- (1) All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report *Implications of Slow or Floating CMOS Inputs*, literature number [SCBA004](#).

5.3 Thermal Information

THERMAL METRIC		D (SOIC)	N (PDIP)	NS (SOP)	UNIT
		16 PINS	16 PINS	16 PINS	
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	73	67	64	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC package thermal metrics](#) application report.

5.4 Electrical Characteristics

PARAMETER		TEST CONDITIONS ⁽¹⁾	V _{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
V _{IH}	High level input voltage		2	1.5			1.5		1.5		V
			4.5	3.15			3.15		3.15		
			6	4.2			4.2		4.2		
V _{IL}	Low level input voltage		2	0.5			0.5		0.5		V
			4.5	1.35			1.35		1.35		
			6	1.8			1.8		1.8		
V _{OH}	High level output voltage CMOS loads	I _{OH} = - 20 μA	2	1.9			1.9		1.9		V
		I _{OH} = - 20 μA	4.5	4.4			4.4		4.4		
		I _{OH} = - 20 μA	6	5.9			5.9		5.9		
	High level output voltage TTL loads	I _{OH} = 4 mA	4.5	3.98			3.84		3.7		V
		I _{OH} = 5.2 mA	6	5.48			5.34		5.2		
	V _{OL}	Low level output voltage CMOS loads	I _{OL} = 20 μA	2	0.1			0.1		0.1	
I _{OL} = 20 μA			4.5	0.1			0.1		0.1		
I _{OL} = 20 μA			6	0.1			0.1		0.1		
Low level output voltage TTL loads		I _{OL} = 4 mA	4.5	0.26			0.33		0.4		V
		I _{OL} = 5.2 mA	6	0.26			0.33		0.4		
I _I		Input leakage current	V _{CC} or GND	6	±0.1			±1		±1	
I _{CC}	Supply current	V _{CC} or GND	6	8			80		160		μA
HCT TYPES											
V _{IH}	High level input voltage		4.5 to 5.5	2			2		2		V
V _{IL}	Low level input voltage		4.5 to 5.5	0.8			0.8		0.8		V
V _{OH}	High level output voltage CMOS loads	I _{OH} = - 20 μA	4.5	4.4			4.4		4.4		V
	High level output voltage TTL loads	I _{OH} = - 4 mA	4.5	3.98			3.84		3.7		V
V _{OL}	Low level output voltage CMOS loads	I _{OL} = 20 μA	4.5	0.1			0.1		0.1		V
	Low level output voltage TTL loads	I _{OL} = 4 mA	4.5	0.26			0.33		0.4		V
I _I	Input leakage current	V _{CC} and GND	5.5	±0.1			±1		±1		μA
I _{CC}	Supply current	V _{CC} or GND	5.5	8			80		160		μA
Δ I _{CC} ⁽²⁾	Additional supply current per input pin	\overline{MR} input held at V _{CC} - 2.1	4.5 to 5.5	100 234			292.5		318.5		μA
		CP input held at V _{CC} - 2.1	4.5 to 5.5	100 180			225		245		μA

(1) V_I = V_{IH} or V_{IL}, unless otherwise noted.

(2) For dual-supply systems theoretical worst case ($V_I = 2.4\text{ V}$, $V_{CC} = 5.5\text{ V}$) specification is 1.8 mA.

5.5 Prerequisite for Switching Characteristics

PARAMETER		V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES										
f_{MAX}	Maximum input pulse frequency	2	6			5		4		MHz
		4.5	30			25		20		
		6	35			29		24		
t_W	Input pulse width	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
t_{REM}	Reset removal time	2	50			65		75		ns
		4.5	10			13		15		
		6	9			11		13		
t_W	Reset pulse width	2	80			100		120		ns
		4.5	16			20		24		
		6	14			17		20		
HCT TYPES										
f_{MAX}	Maximum input pulse frequency	4.5	25			20		16		MHz
t_W	Input pulse width	4.5	20			25		30		ns
t_{REC}	Reset recovery time	4.5	10			13		15		ns
t_W	Reset pulse width	4.5	20			25		30		ns

5.6 Switching Characteristics

Input t_r , $t_f = 6\text{ ns}$. See [Parameter Measurement Information](#)

PARAMETER		TEST CONDITIONS	V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
t_{PLH} , t_{PHL}	Propagation delay time CP to Q1' Output	$C_L = 50\text{ pF}$	2	140			175		210		ns
			4.5	28			35		42		
		$C_L = 15\text{ pF}$	5	11							
			6	24			30		36		
t_{PLH} , t_{PHL}	Qn to Qn + 1	$C_L = 50\text{ pF}$	2	75			95		110		ns
			4.5	15			19		22		
		$C_L = 15\text{ pF}$	5	4							
			6	13			16		19		
t_{PLH} , t_{PHL}	MR to Qn	$C_L = 50\text{ pF}$	2	170			215		255		ns
			4.5	34			43		51		
			5	14							
			6	29			37		43		
t_{TLH} , t_{THL}	Output transition time	$C_L = 50\text{ pF}$	2	75			95		110		ns
			4.5	15			19		22		
			6	13			16		19		
C_{IN}	Input capacitance	$C_L = 50\text{ pF}$		10			10		10		pF
C_{PD}	Power dissipation capacitance ^{(1) (2)}	$C_L = 15\text{ pF}$	5	40							pF
HCT TYPES											

5.6 Switching Characteristics (continued)

Input t_r , t_f = 6 ns. See [Parameter Measurement Information](#)

PARAMETER		TEST CONDITIONS	V_{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH} , t_{PHL}	Propagation delay time	$C_L = 50$ pF	4.5		40		50		60	ns	
	CP to Q1' Output	$C_L = 15$ pF	5	17							
t_{PLH} , t_{PHL}	Qn to Q _n + 1	$C_L = 50$ pF	4.5		15		19		22	ns	
		$C_L = 15$ pF	5	4							
t_{PLH} , t_{PHL}	MR to Q _n	$C_L = 50$ pF	4.5		40		50		60	ns	
		$C_L = 15$ pF	5	17							
t_{TLH} , t_{THL}	Output transition	$C_L = 50$ pF	4.5		15		19		22	ns	
C_{IN}	Input capacitance	$C_L = 50$ pF			10		10		10	pF	
C_{PD}	Power dissipation capacitance ^{(1) (2)}	$C_L = 15$ pF	5		45					pF	

(1) C_{PD} is used to determine the dynamic power consumption, per package.

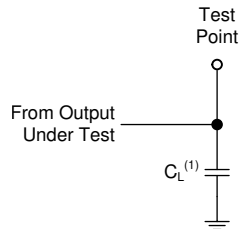
(2) $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = Input frequency, C_L = Output load capacitance, V_{CC} = Supply Voltage.

6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, $t_t < 6 \text{ ns}$.

For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C_L includes probe and test-fixture capacitance.

图 6-1. Load Circuit for Push-Pull Outputs

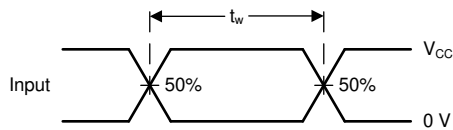


图 6-2. Voltage Waveforms, Standard CMOS Inputs Pulse Duration

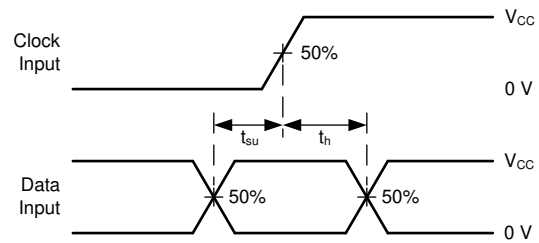
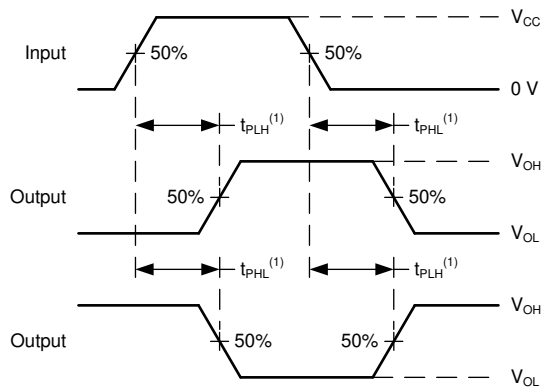
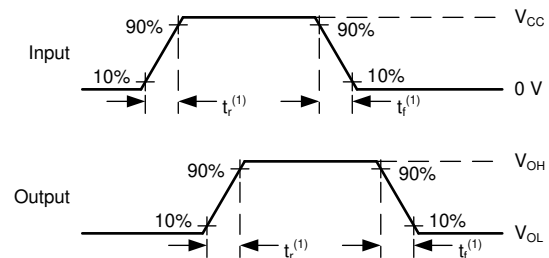


图 6-3. Voltage Waveforms, Standard CMOS Inputs Setup and Hold Times



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

图 6-4. Voltage Waveforms, Propagation Delays for Standard CMOS Inputs



(1) The greater between t_r and t_f is the same as t_t .

图 6-5. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs

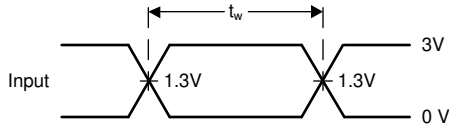


图 6-6. Voltage Waveforms, TTL-Compatible CMOS Inputs Pulse Duration

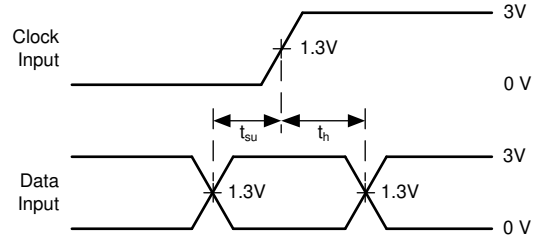
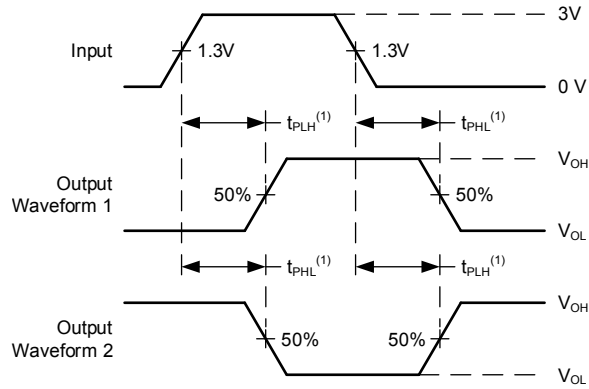


图 6-7. Voltage Waveforms, TTL-Compatible CMOS Inputs Setup and Hold Times



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

图 6-8. Voltage Waveforms, Propagation Delays for TTL-Compatible Inputs

7 Detailed Description

7.1 Overview

The ' HC4040 and ' HCT4040 are 14-stage ripple-carry binary counters. All counter stages are controller flipflops. The state of the stage advances one count on the negative clock transition of each input pulse; a high voltage level on the MR line resets all counters to their zero state. All inputs and outputs are buffered.

7.2 Functional Block Diagram

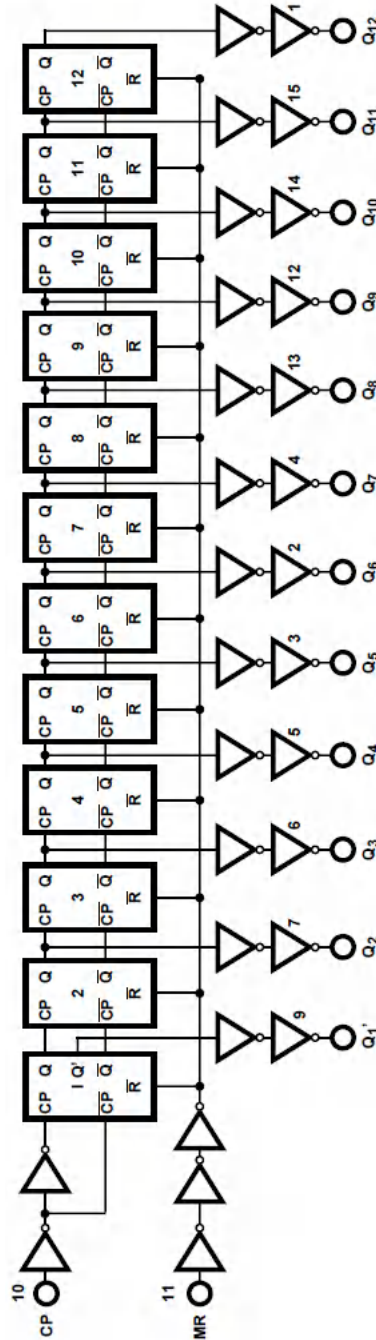


图 7-1. Functional Block Diagram

7.3 Device Functional Modes

**Function Table
(Each Flip-Flop)⁽¹⁾**

CP COUNT	MR	OUTPUT STATE
↑	L	No Change
↓	L	Advance to Next State
X	H	All Outputs Are Low

(1) H = High voltage level, L = Low voltage level, X = Don't care, ↑ = Transition time from low to high level, ↓ = Transition from high to low.

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Documentation Support

10.1.1 Related Documentation

10.2 接收文档更新通知

要接收文档更新通知，请导航至 ti.com 上的器件产品文件夹。点击 [订阅更新](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

10.3 支持资源

TI E2E™ [支持论坛](#) 是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [《使用条款》](#)。

10.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8994701MEA	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8994701ME A CD54HCT4040F3A	Samples
CD54HC4040F	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HC4040F	Samples
CD54HC4040F3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8500401EA CD54HC4040F3A	Samples
CD54HCT4040F3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8994701ME A CD54HCT4040F3A	Samples
CD74HC4040E	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC4040E	Samples
CD74HC4040M	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	HC4040M	
CD74HC4040M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HC4040M	Samples
CD74HCT4040E	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT4040E	Samples
CD74HCT4040M	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	HCT4040M	
CD74HCT4040M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT4040M	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD54HC4040, CD54HCT4040, CD74HC4040, CD74HCT4040 :

- Catalog : [CD74HC4040](#), [CD74HCT4040](#)
- Military : [CD54HC4040](#), [CD54HCT4040](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4040M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT4040M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4040M96	SOIC	D	16	2500	356.0	356.0	35.0
CD74HCT4040M96	SOIC	D	16	2500	340.5	336.1	32.0

TUBE


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CD74HC4040E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC4040E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT4040E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT4040E	N	PDIP	16	25	506	13.97	11230	4.32

J (R-GDIP-T**)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



DIM \ PINS **	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



4040083/F 03/03

- NOTES:
- All linear dimensions are in inches (millimeters).
 - This drawing is subject to change without notice.
 - This package is hermetically sealed with a ceramic lid using glass frit.
 - Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
 - Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



4040049/E 12/2002

- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
 - The 20 pin end lead shoulder width is a vendor option, either half or full width.

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
 - D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
 - E. Reference JEDEC MS-012 variation AC.

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